

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1680	PRIORITY SERIAL NO. 09/512,968		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					PRIORITY FILING DATE February 24, 2000	PRIORITY GROUP 2858		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa				
VN	AB	4,754,555	7/5/88	Stillman				
VN	AC	5,475,317	12/12/95	Smith				
VN	AD	5,495,667	3/5/96	Farnworth et al.				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
VN	AE	S/N: 09/032,184; Filed 2/27/98; Alram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/99;						
		Original Application filed 2/27/98; Pending Claims.						
VN	AF	Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc., 1 page; 3/6/98						
VN	AG	Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98						
VN	AH	Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Densi America, Inc.; 1 page; 2/4/98.						
VN	AI	Product Description for Test Centers, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Densi America, Inc.; 1 page; 2/4/98.						
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Densi America, Inc.;						
		1 page; 2/4/98.						
VN	AK	Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Densi America, Inc.; 1 page; 2/4/98.						
VN	AL	Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98						
EXAMINER		<i>Mark Nguyen</i>		DATE CONSIDERED		02/07/2002		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

11000 S. Pro
4/825664
04/03/01

EL 465855340

Form PTO-1449 JUL 06 2001 PATENT & TRADEMARK OFFICE		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1680		SERIAL NO. 09/825,664	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					FILING DATE April 3, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
VN	AA	5,378,311	1/3/95	Nagayama et al.		—	—	
	AB							
	AC							
	AD							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
EXAMINER <i>mark Nguyen</i>				DATE CONSIDERED 02/07/2002				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								